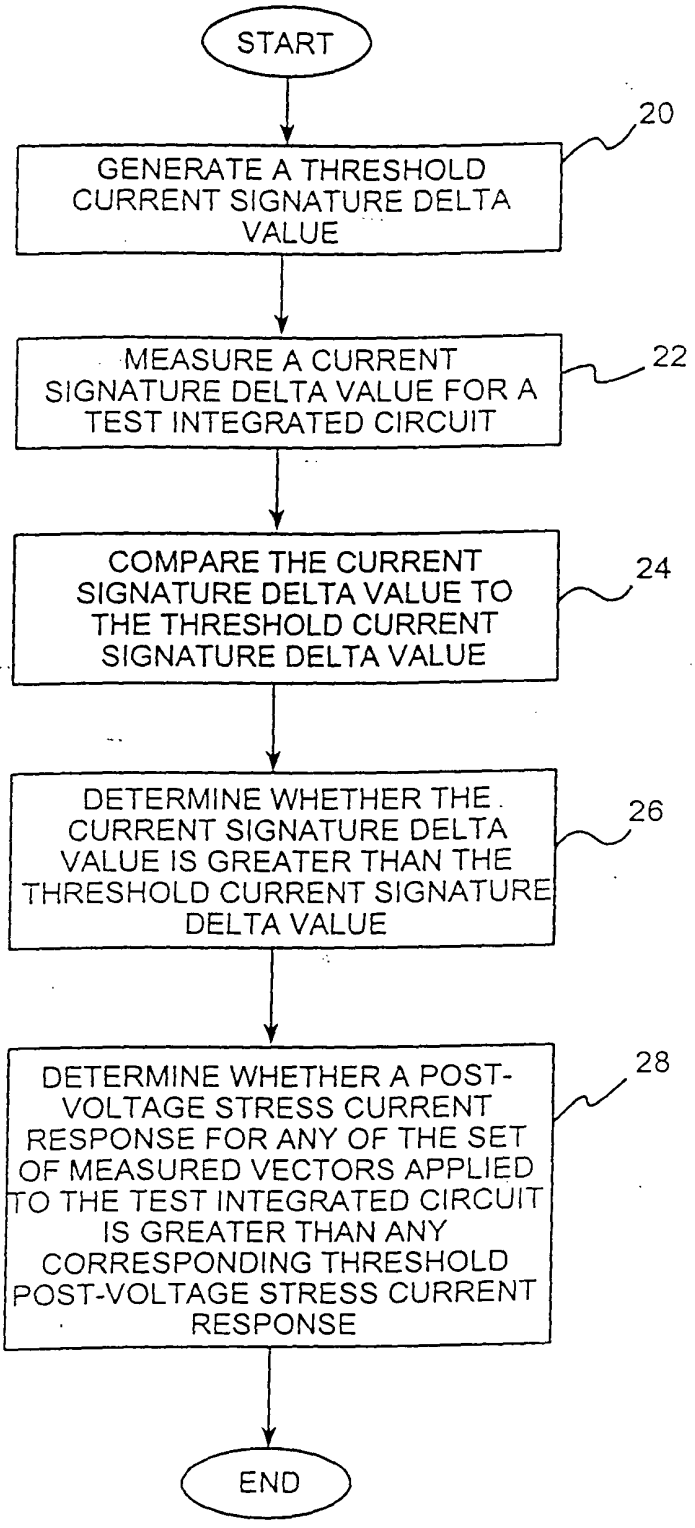
START
GENERATE A THRESHOLD CURRENT SIGNATURE DELTA VALUE
20
MEASURE A CURRENT SIGNATURE DELTA VALUE FOR A TEST INTEGRATED CIRCUIT
22
COMPARE THE CURRENT SIGNATURE DELTA VALUE TO THE THRESHOLD CURRENT SIGNATURE DELTA VALUE
24
DETERMINE WHETHER THE CURRENT SIGNATURE DELTA VALUE IS GREATER THAN THE THRESHOLD CURRENT SIGNATURE DELTA VALUE
26
DETERMINE WHETHER A POST-VOLTAGE STRESS CURRENT RESPONSE FOR ANY OF THE SET OF MEASURED VECTORS APPLIED TO THE TEST INTEGRATED CIRCUIT IS GREATER THAN ANY CORRESPONDING THRESHOLD POST-VOLTAGE STRESS CURRENT RESPONSE
28
END

FIG. 1

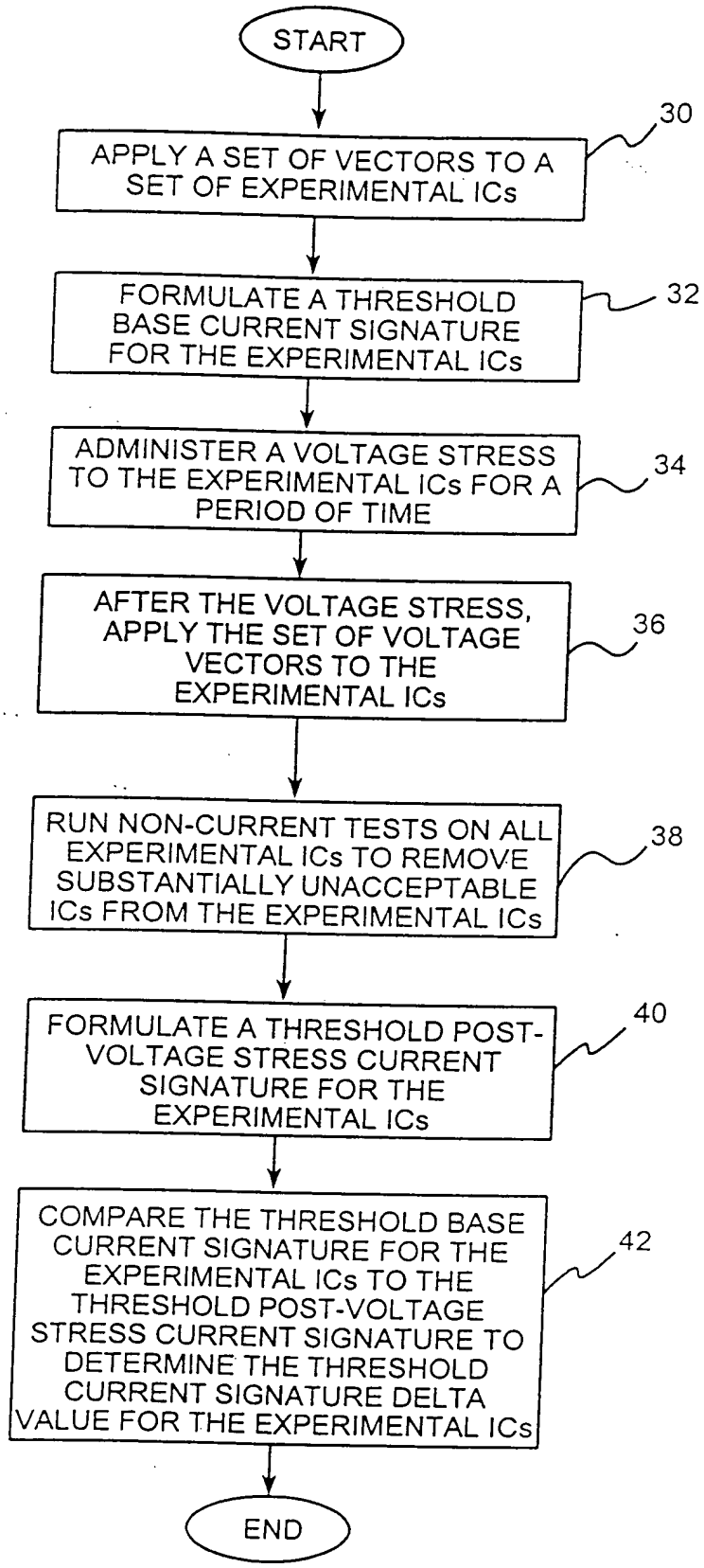
START
APPLY A SET OF VECTORS TO A SET OF EXPERIMENTAL ICs
30
FORMULATE A THRESHOLD BASE CURRENT SIGNATURE FOR THE EXPERIMENTAL ICs
32
ADMINISTER A VOLTAGE STRESS TO THE EXPERIMENTAL ICs FOR A PERIOD OF TIME
34
AFTER THE VOLTAGE STRESS, APPLY THE SET OF VOLTAGE VECTORS TO THE EXPERIMENTAL ICs
36
RUN NON-CURRENT TESTS ON ALL EXPERIMENTAL ICs TO REMOVE SUBSTANTIALLY UNACCEPTABLE ICs FROM THE EXPERIMENTAL ICs
38
FORMULATE A THRESHOLD POST-VOLTAGE STRESS CURRENT SIGNATURE FOR THE EXPERIMENTAL ICs
40
COMPARE THE THRESHOLD BASE CURRENT SIGNATURE FOR THE EXPERIMENTAL ICs TO THE THRESHOLD POST-VOLTAGE STRESS CURRENT SIGNATURE TO DETERMINE THE THRESHOLD CURRENT SIGNATURE DELTA VALUE FOR THE EXPERIMENTAL ICs
42
END

FIG. 2

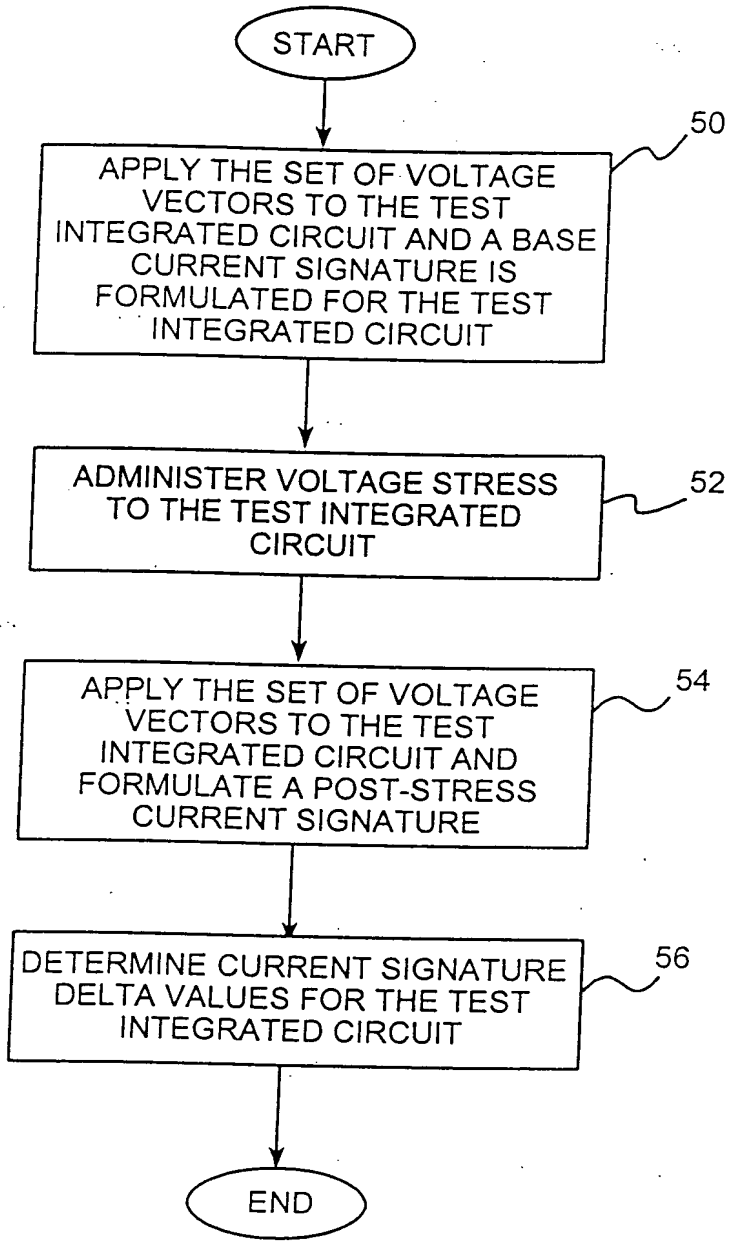
START
APPLY THE SET OF VOLTAGE VECTORS TO THE TEST INTEGRATED CIRCUIT AND A BASE CURRENT SIGNATURE IS FORMULATED FOR THE TEST INTEGRATED CIRCUIT
50
ADMINISTER VOLTAGE STRESS TO THE TEST INTEGRATED CIRCUIT
52
APPLY THE SET OF VOLTAGE VECTORS TO THE TEST INTEGRATED CIRCUIT AND FORMULATE A POST-STRESS CURRENT SIGNATURE
54
DETERMINE CURRENT SIGNATURE DELTA VALUES FOR THE TEST INTEGRATED CIRCUIT
56
END

FIG. 3

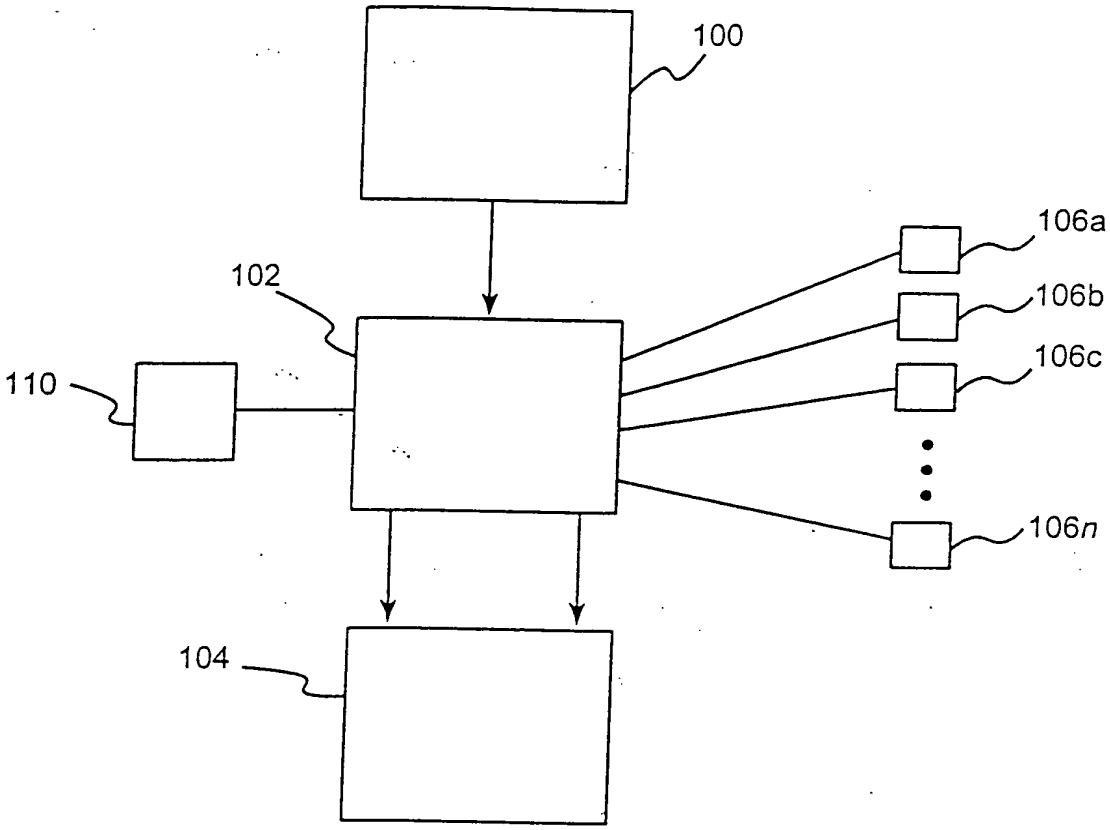


FIG. 4